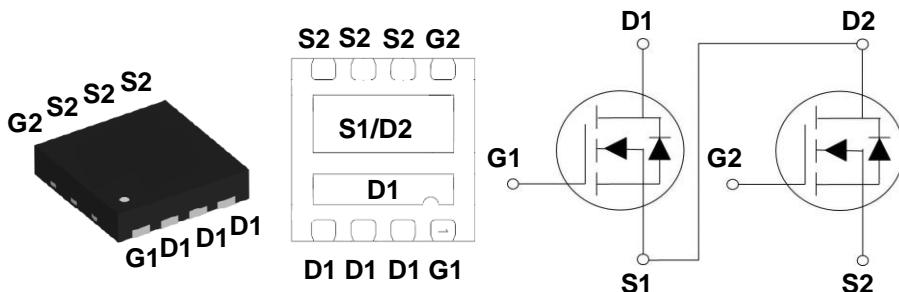


### General Description

These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

### DFN3x3 Asymmetric Dual Pin Configuration



	BVDSS	RDS(on)	ID
Q1	30V	10.5mΩ	19.5A
Q2	30V	10.5mΩ	19.5A

### Features



- Improved dv/dt capability
- Fast switching
- 100% EAS Guaranteed
- Halogen free

### Applications

- MB / VGA / Vcore
- POL Buck Applications
- SMPS 2<sup>nd</sup> SR

### Absolute Maximum Ratings T<sub>c</sub>=25°C unless otherwise noted

Symbol	Parameter	Q1	Q2	Units
V <sub>DS</sub>	Drain-Source Voltage	30	30	V
V <sub>GS</sub>	Gate-Source Voltage	±20	±20	V
I <sub>D</sub>	Drain Current – Continuous (T <sub>c</sub> =25°C)	19.5	19.5	A
	Drain Current – Continuous (T <sub>c</sub> =100°C)	12.3	12.3	A
	Drain Current – Continuous (T <sub>A</sub> =25°C)	10.8	10.8	A
	Drain Current – Continuous (T <sub>A</sub> =100°C)	6.8	6.8	A
I <sub>DM</sub>	Drain Current – Pulsed <sup>1</sup>	78	78	A
EAS	Single Pulse Avalanche Energy <sup>2</sup>	13	13	mJ
IAS	Single Pulse Avalanche Current <sup>2</sup>	16	16	A
P <sub>D</sub>	Power Dissipation (T <sub>c</sub> =25°C)	27	27	W
	Power Dissipation – Derate above 25°C	0.01	0.01	W/°C
T <sub>STG</sub>	Storage Temperature Range	-55 to 150		°C
T <sub>J</sub>	Operating Junction Temperature Range	-55 to 150		°C

### Electrical Characteristics (T<sub>J</sub>=25 °C, unless otherwise noted)

Symbol	Parameter	Typ.	Max.	Unit
R <sub>θJA</sub>	Q1	Thermal Resistance Junction to ambient	---	62
R <sub>θJA</sub>			---	62
R <sub>θJC</sub>	Q1	Thermal Resistance Junction to Case	---	4.6
R <sub>θJC</sub>			---	4.6

### Static State Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV <sub>DSS</sub>	Drain-Source Breakdown Voltage	V <sub>GS</sub> =0V , I <sub>D</sub> =250uA	Q1	30	---	---
			Q2	30	---	---
$\Delta BV_{DSS}/\Delta T_J$	BV <sub>DSS</sub> Temperature Coefficient	Reference to 25°C , I <sub>D</sub> =1mA	Q1	---	0.04	---
			Q2	---	0.04	---
I <sub>DSS</sub>	Drain-Source Leakage Current	V <sub>DS</sub> =30V , V <sub>GS</sub> =0V , T <sub>J</sub> =25°C	Q1	---	---	1 uA
		Q2	---	---	1 uA	
		V <sub>DS</sub> =24V , V <sub>GS</sub> =0V , T <sub>J</sub> =125°C	Q1	---	---	10 uA
		Q2	---	---	10 uA	
I <sub>GSS</sub>	Gate-Source Leakage Current	V <sub>GS</sub> =±20V , V <sub>DS</sub> =0V	Q1	---	---	±100 nA
			Q2	---	---	±100 nA
R <sub>DSON</sub>	Static Drain-Source On-Resistance <sup>3</sup>	V <sub>GS</sub> =10V , I <sub>D</sub> =10A	Q1	---	8.5	10.5 mΩ
		V <sub>GS</sub> =10V , I <sub>D</sub> =10A	Q2	---	8.5	10.5 mΩ
		V <sub>GS</sub> =4.5V , I <sub>D</sub> =5A	Q1	---	11	14 mΩ
		V <sub>GS</sub> =4.5V , I <sub>D</sub> =5A	Q2	---	11	14 mΩ
V <sub>GS(th)</sub>	Gate Threshold Voltage	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	Q1	1.2	1.6	2.5 V
			Q2	1.2	1.6	2.5 V
$\Delta V_{GS(th)}$	V <sub>GS(th)</sub> Temperature Coefficient	V <sub>GS</sub> =V <sub>DS</sub> , I <sub>D</sub> =250uA	Q1	---	-4	---
			Q2	---	-4	---
g <sub>f</sub>	Forward Transconductance	V <sub>DS</sub> =5V , I <sub>D</sub> =5A	Q1	---	12	---
		V <sub>DS</sub> =5V , I <sub>D</sub> =5A	Q2	---	12	---

### Dynamic Characteristics

Q <sub>g</sub>	Total Gate Charge <sup>3, 4</sup>	V <sub>DS</sub> =15V , V <sub>GS</sub> =10V , I <sub>D</sub> =5A	Q1	---	15.6	31	nC	
			Q2	---	15.6	31		
Q <sub>gs</sub>	Gate-Source Charge <sup>3, 4</sup>		Q1	---	2.3	5		
			Q2	---	2.3	5		
Q <sub>gd</sub>	Gate-Drain Charge <sup>3, 4</sup>		Q1	---	3	6		
			Q2	---	3	6		
T <sub>d(on)</sub>	Turn-On Delay Time <sup>3, 4</sup>	V <sub>DD</sub> =15V , V <sub>GS</sub> =10V , R <sub>G</sub> =6Ω I <sub>D</sub> =1A	Q1	---	3.8	7	ns	
			Q2	---	3.8	7		
T <sub>r</sub>	Rise Time <sup>3, 4</sup>		Q1	---	10	19		
			Q2	---	10	19		
T <sub>d(off)</sub>	Turn-Off Delay Time <sup>3, 4</sup>		Q1	---	22	42		
			Q2	---	22	42		
T <sub>f</sub>	Fall Time <sup>3, 4</sup>		Q1	---	6.6	13		
			Q2	---	6.6	13		

$C_{iss}$	Input Capacitance	$V_{DS}=25V, V_{GS}=0V, F=1MHz$	Q1	---	620	900	pF
$C_{oss}$	Output Capacitance		Q2	---	620	900	
$C_{rss}$	Reverse Transfer Capacitance		Q1	---	85	125	
$C_{rss}$	Reverse Transfer Capacitance		Q2	---	85	125	
$R_g$	Gate resistance		Q1	---	60	90	
$R_g$	Gate resistance		Q2	---	60	90	
$V_{GS}=0V, V_{DS}=0V, F=1MHz$		$V_{GS}=0V, V_{DS}=0V, F=1MHz$	Q1	---	2.8	5.6	$\Omega$
$V_{GS}=0V, V_{DS}=0V, F=1MHz$			Q2	---	2.8	5.6	$\Omega$

### Drain-Source Diode Characteristics

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
$I_s$	Continuous Source Current	$V_G=V_D=0V, \text{Force Current}$	Q1	---	---	19.5 A
$I_{SM}$	Pulsed Source Current <sup>3</sup>		Q2	---	---	19.5 A
$I_{SM}$	Pulsed Source Current <sup>3</sup>		Q1	---	---	39 A
$I_{SM}$	Pulsed Source Current <sup>3</sup>		Q2	---	---	39 A
$V_{SD}$	Diode Forward Voltage <sup>3</sup>	$V_{GS}=0V, I_s=1A, T_J=25^\circ C$	Q1	---	---	1 V
$V_{SD}$	Diode Forward Voltage <sup>3</sup>		Q2	---	---	1 V

Note :

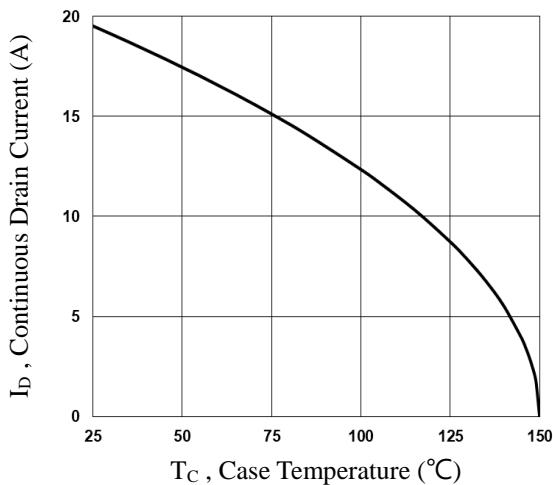
1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
2.  $V_{DD}=25V, V_{GS}=10V, L=0.1mH, Q1: I_{AS}=16A, Q2: I_{AS}=42A, R_G=25\Omega, \text{Starting } T_J=25^\circ C$ .
3. The data tested by pulsed , pulse width  $\leq 300\mu s$  , duty cycle  $\leq 2\%$ .
4. Essentially independent of operating temperature.



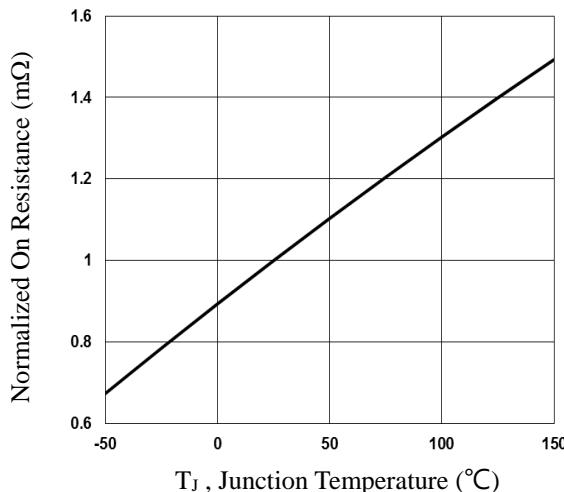
STEIF POWER  
TECHNOLOGY

30V N-Channel MOSFETs

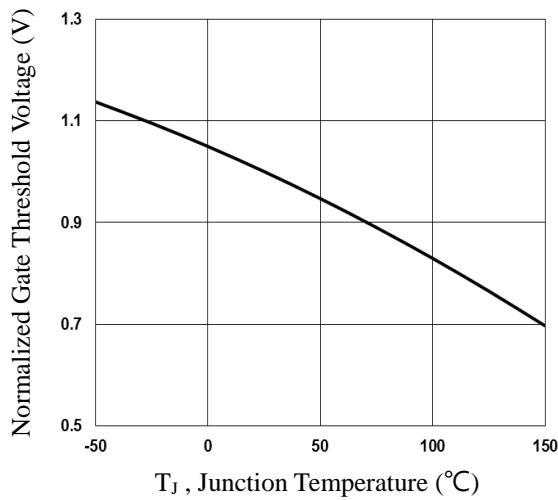
**SPB3810H**



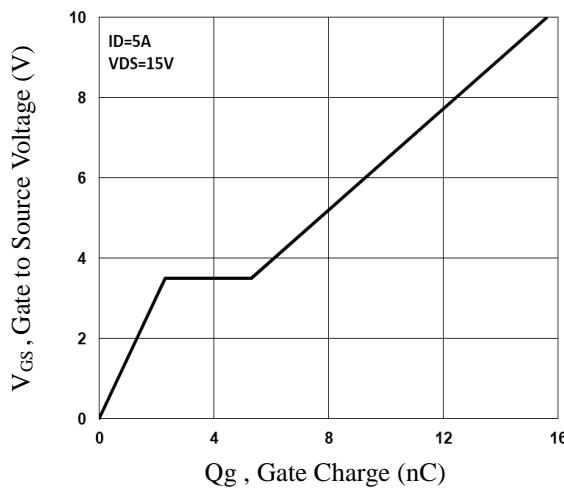
**Fig.1 Q1 Continuous Drain Current vs.  $T_c$**



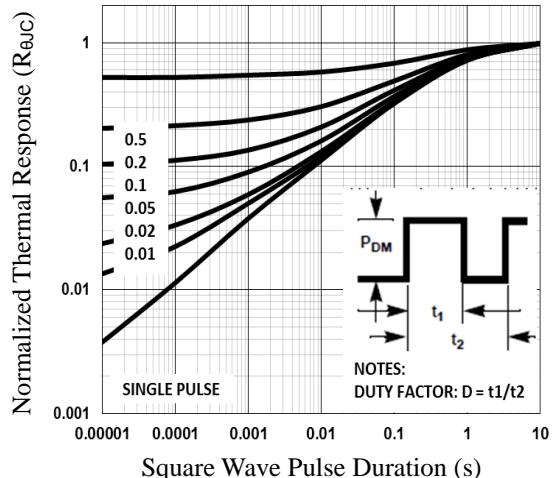
**Fig.2 Q1 Normalized  $R_{DS(on)}$  vs.  $T_J$**



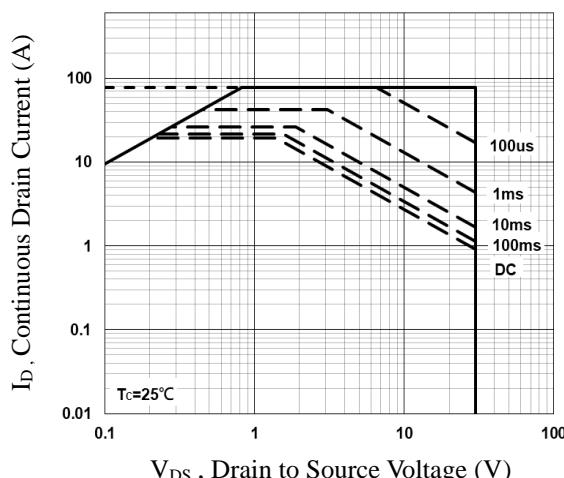
**Fig.3 Q1 Normalized  $V_{th}$  vs.  $T_J$**



**Fig.4 Q1 Gate Charge Waveform**



**Fig.5 Q1 Normalized Transient Impedance**



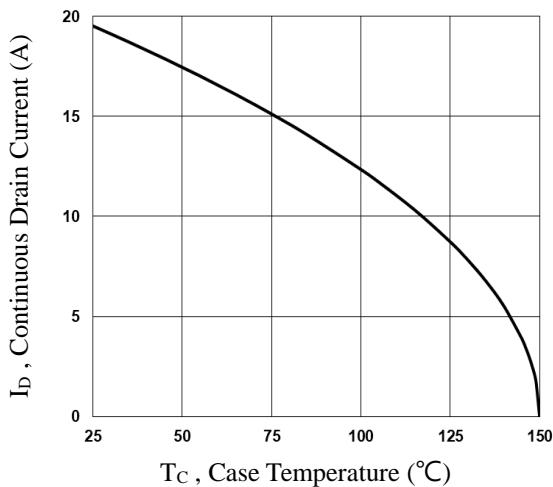
**Fig.6 Q1 Maximum Safe Operation Area**



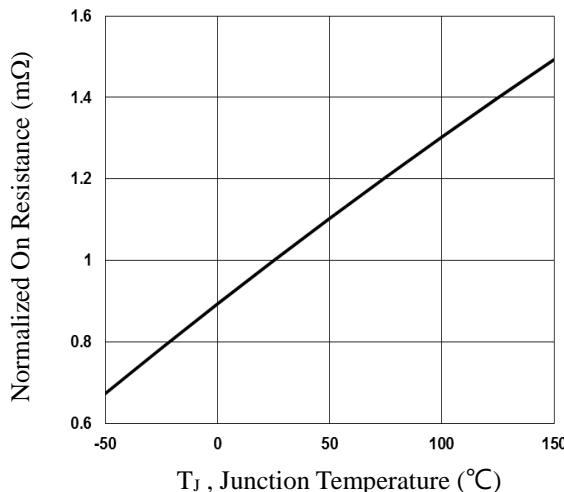
STEIF POWER  
TECHNOLOGY

30V N-Channel MOSFETs

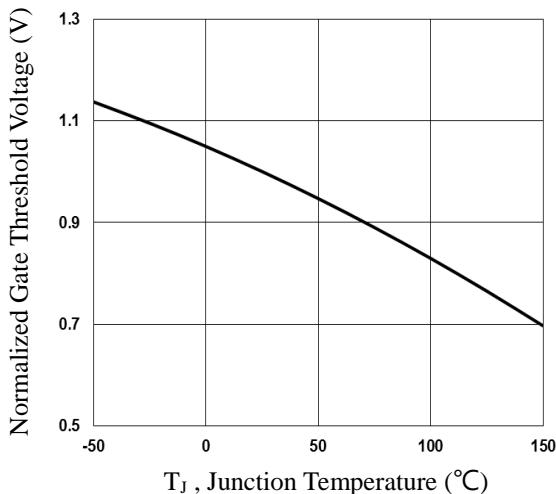
**SPB3810H**



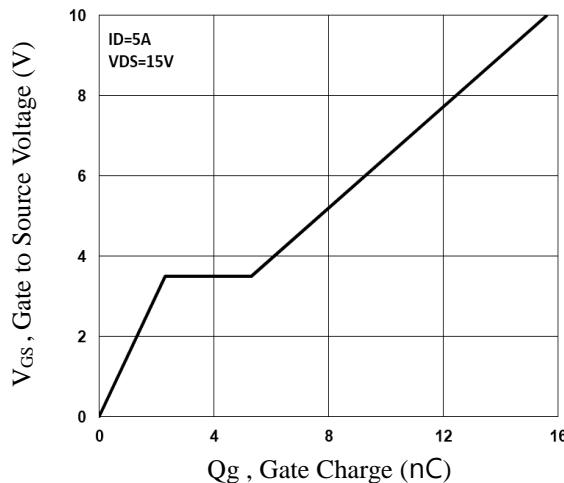
**Fig.7 Q2 Continuous Drain Current vs.  $T_c$**



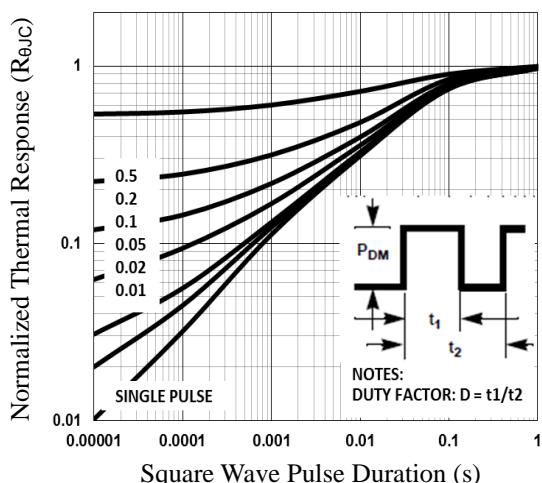
**Fig.8 Q2 Normalized  $R_{DS(on)}$  vs.  $T_J$**



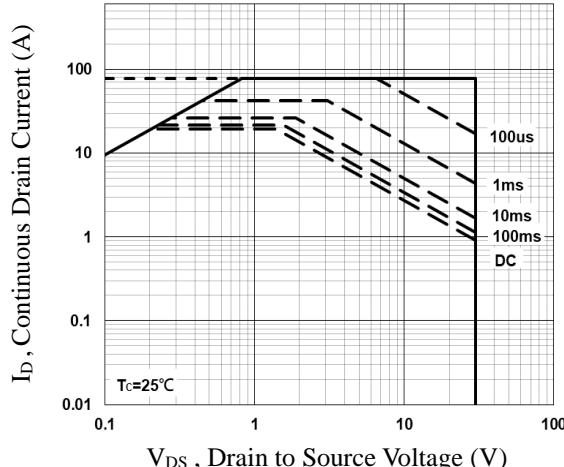
**Fig.9 Q2 Normalized  $V_{th}$  vs.  $T_J$**



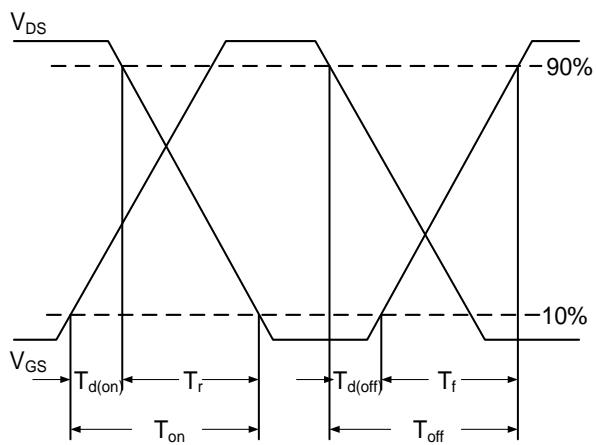
**Fig.10 Q2 Gate Charge Waveform**



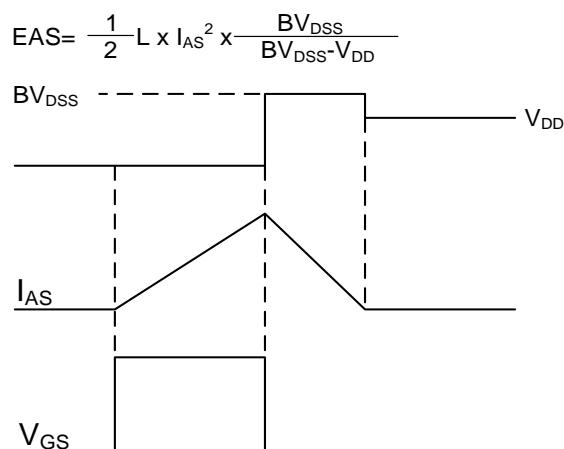
**Fig.11 Q2 Normalized Transient Impedance**



**Fig.12 Q2 Maximum Safe Operation Area**



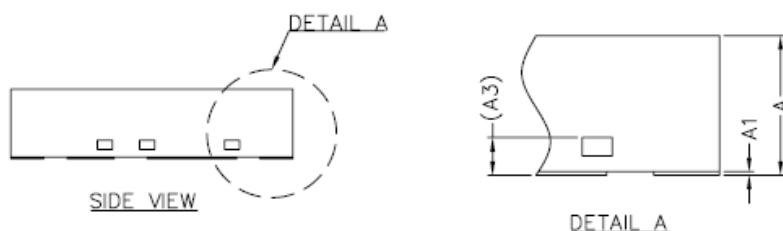
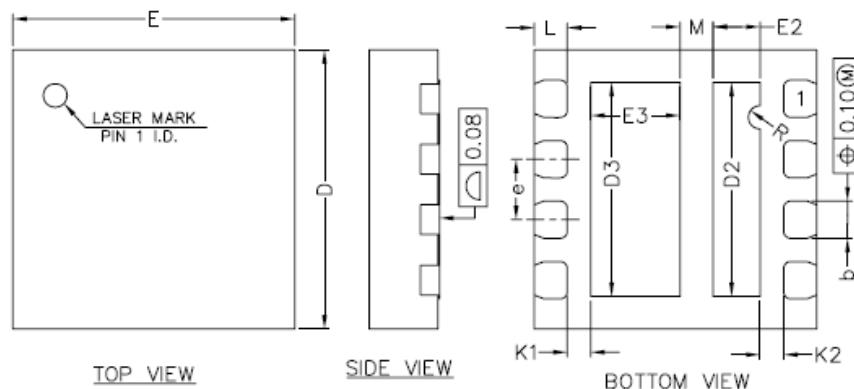
**Fig.13 Switching Time Waveform**



**Fig.14 EAS Waveform**

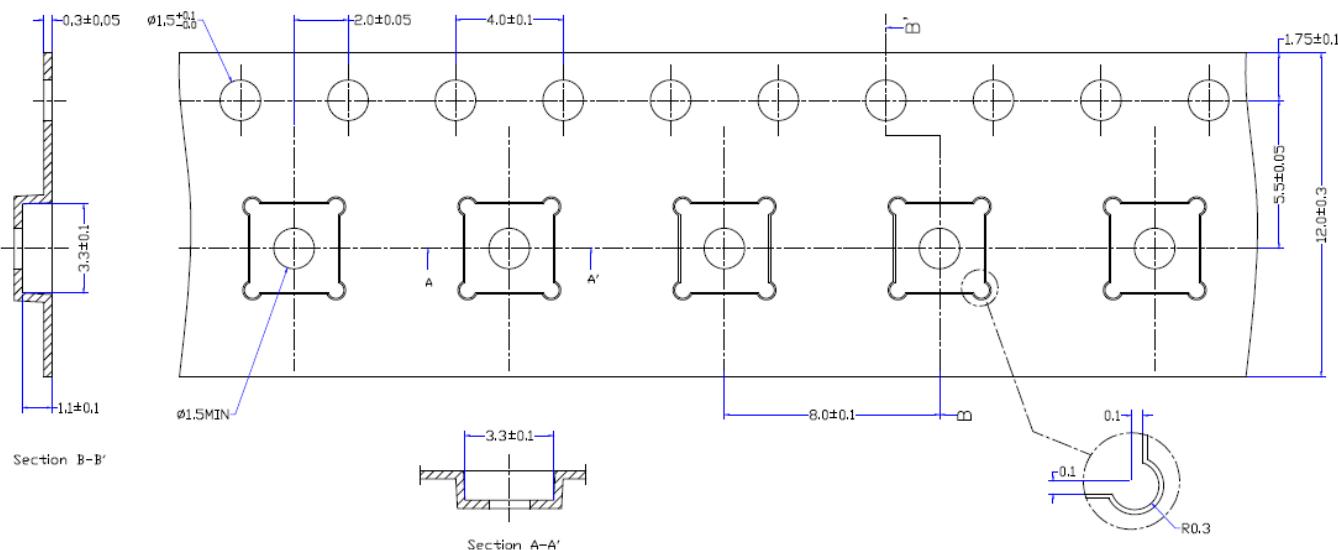


## DFN3x3 Asymmetric Dual Package Information



Symbol	Dimensions In Millimeters		
	Min	Typ	Max
A	0.70	0.75	0.80
A1	0.00	0.02	0.05
A3	0.20REF		
b	0.35	0.40	0.45
D	2.90	3.00	3.10
E	2.90	3.00	3.10
D2	2.20	2.30	2.40
E2	0.40	0.50	0.60
D3	2.20	2.30	2.40
E3	0.85	0.95	1.05
e	0.55	0.65	0.75
K1	0.15	0.25	0.35
K2	0.15	0.25	0.35
L	0.30	0.35	0.40
M	0.25	0.35	0.45
R	0.125REF		

## TAPE & REEL Information



## NOTES:

- NOTES:

  - 1.10 procket hole pitch cumulative tolerance  $\pm 0.2$
  - 2.The meander of the tape is assumed with 1mm or less every 100mm between 250mm
  - 3.MATERIAL:CONDUCTIVE POYSTYRENE
  - 4.ALL DIMS IN MM
  - 5.There must not be foreign body adhesion and the state of the surface must be excellent
  - 6.17" PAPER-Reel, 77500pockets(620m)
  - 7.Surface resistance  $1 \times 10^5 \sim 1 \times 10^9$  OHMS/SQ

# RECOMMEND FOOTPRINT Information

